



SURFIEW

3D Surface Profiler

SURFIEW

3D Surface Profiler

Faster
Accurately
Sincerely
Trust



GLTECH 3D Measurement Solutions



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3차원 형상 측정

개요

3차원 형상 측정기는 빛의 간섭을 이용해서 높이 분해능이 0.1nm로서 1nm ~ 10mm의 표면 형상을 쉽고, 빠르고, 정확하게 나노 단위로 측정합니다. 접촉식 방식에 비해서 측정물의 손상이 전혀 없으며 공초점 방식에 비해서 렌즈 배율에 상관없이 높이 분해능이 동일하기 때문에 정확하게 측정이 가능하고 AFM 방식에 비해서 빠르고 넓은 영역의 측정이 가능합니다.

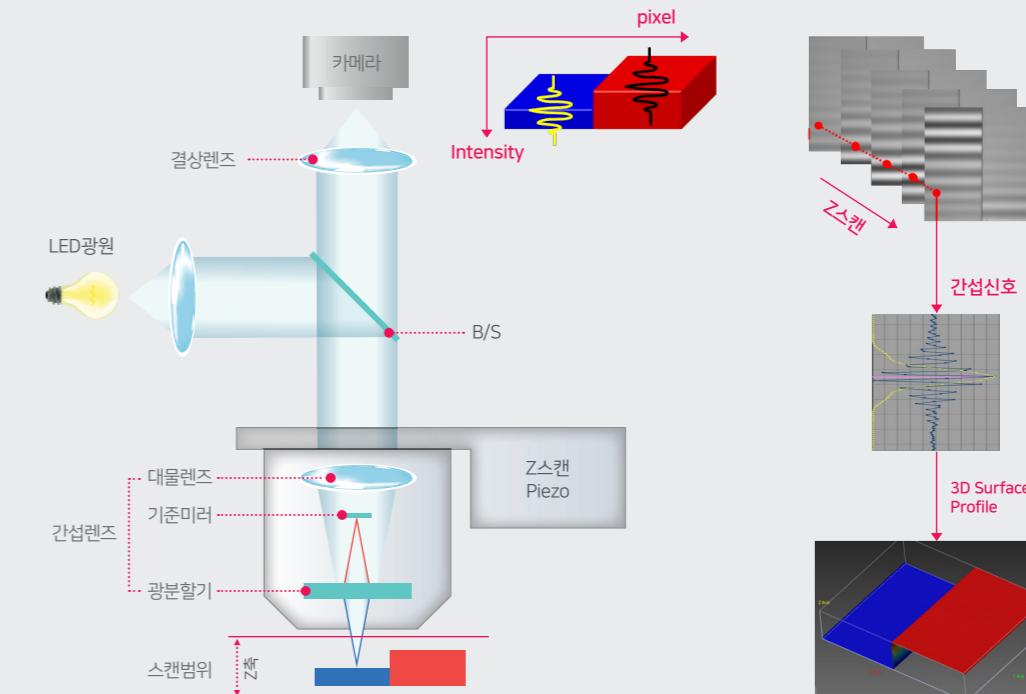
측정

- 2D형상, 3D형상을 동시 측정
- 높이, 깊이, 단자, 선, 원, 호, 각도, 폭, 거리측정
- 면적 거칠기(ISO-25178), 라인 거칠기(ISO-4287), 파형 측정
- 스크래치, 마모, 결함, 단면적, 부피 측정

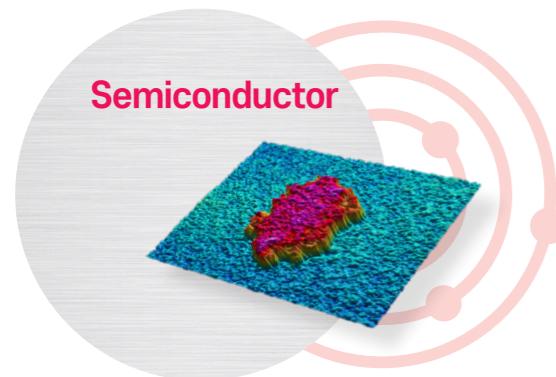
특징

- 높이 분해능 0.1nm로 측정
- 다양한 FOV 사이즈로 측정 가능
- 배율에 상관없이 동일한 분해능
- 투명, 반투명, 불투명 등의 다양한 샘플 측정 가능
- 쉽고, 빠르고, 정밀하게 측정 가능
- Piezo와 Closed loop에 의한 높은 신뢰성
- 장비 상태 모니터링 기능 탑재
- Gage R&R이 우수함

제품 원리



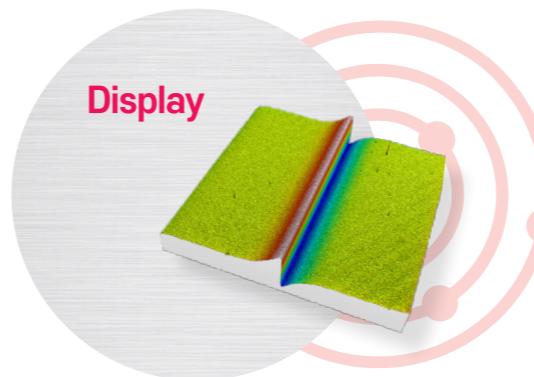
응용 분야



Semiconductor

Stud Bump
CMP
CVD
Wafer

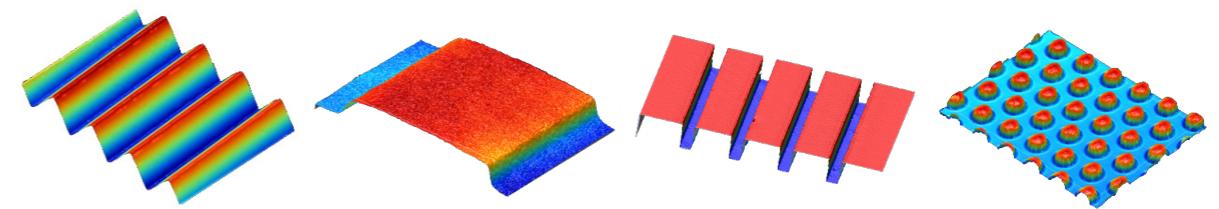
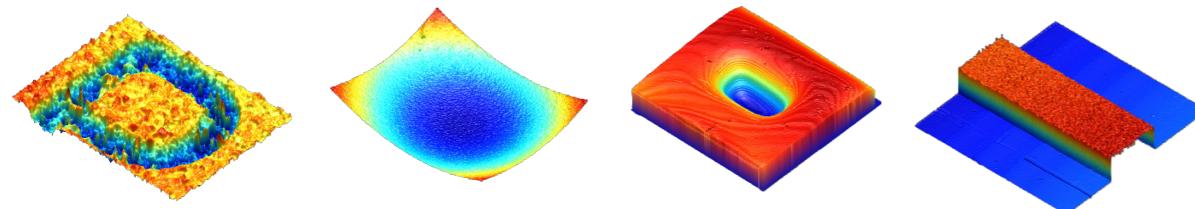
높이, 두께, 깊이, 스크래치,
거칠기, 파형, Warpage,
Coplanarity, 지름, 폭,
각도, 부피, 면적, 진원도



Display

Photo Space
RGB
TFT Pattern
BLU
Metal Jet
Glass
OLED

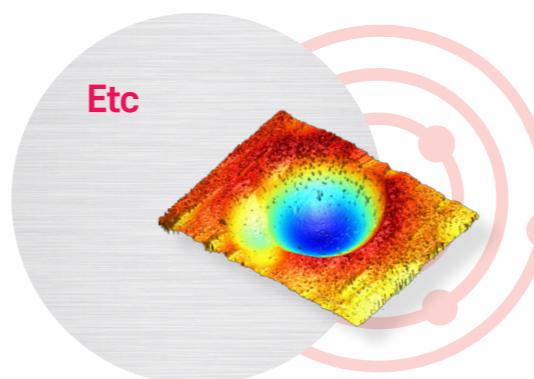
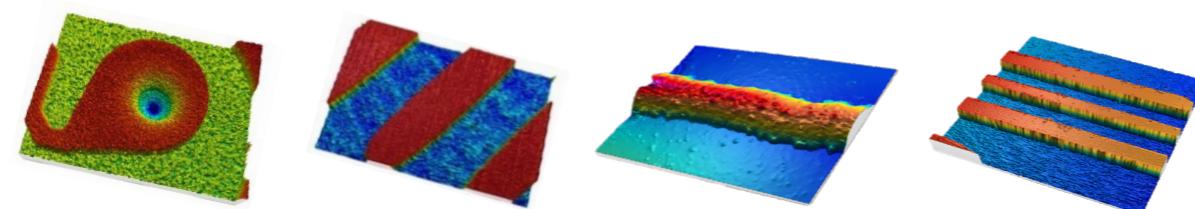
높이, 두께, 깊이, 스크래치,
거칠기, 파형, Warpage,
Coplanarity, 지름, 폭,
각도, 부피, 면적, 진원도



PCB Substrate

Substrate
(Pad, Trace, Space,
Anchor, Land,
Ball Pad, Via Hole,
Dimple, SR)
BGA

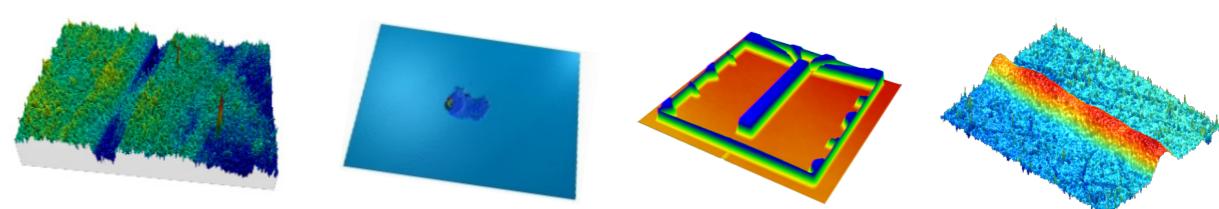
높이, 두께, 깊이, 스크래치,
거칠기, 파형, Warpage,
Coplanarity, 지름, 폭,
각도, 부피, 면적, 진원도



Etc

MEMS
Precision
machine part
Laser Marking
Inkjet
Solar
Micro Lens
Hardness
Battery
Bio
RFID

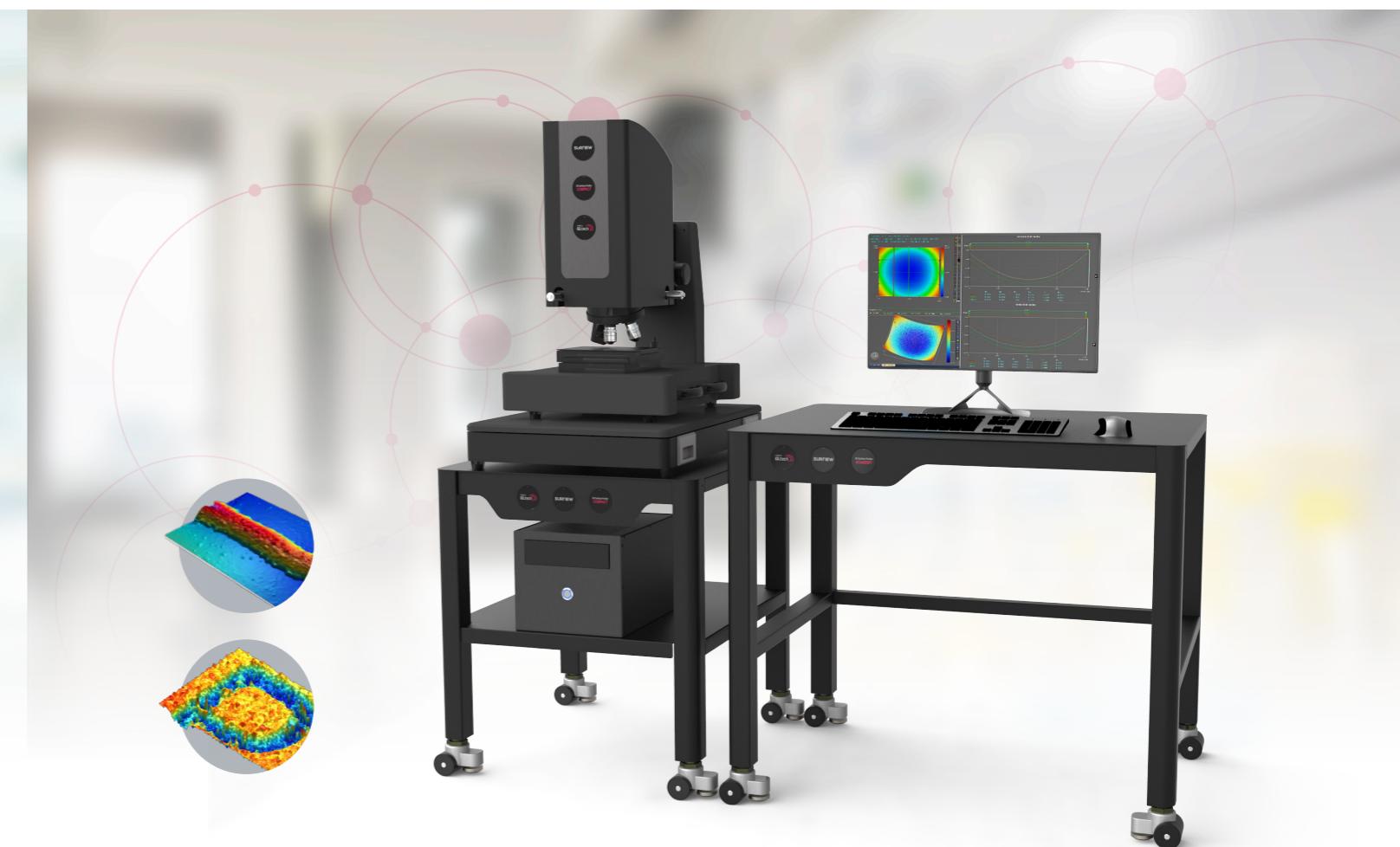
높이, 두께, 깊이, 스크래치,
거칠기, 파형, Warpage,
Coplanarity, 지름, 폭,
각도, 부피, 면적, 진원도



SURVIEW ACADEMY SERIES



SURVIEW COMPACT SERIES



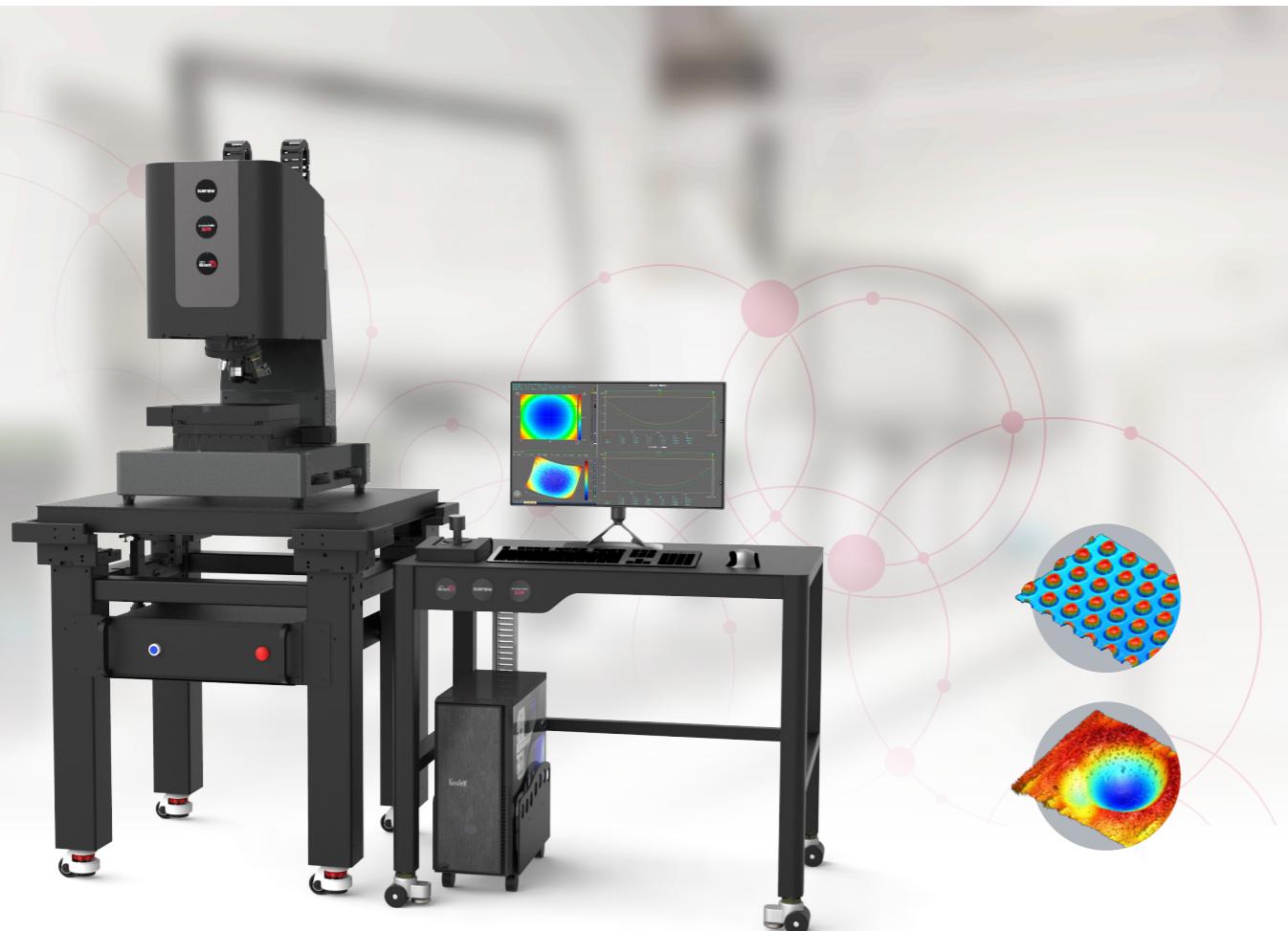
Specification

Vertical Resolution	VSI, VEI < 0.5nm, VPI < 0.1nm	Sample Reflectivity	0.05 ~ 100%
Pixel Resolution	0.03 ~ 7.2um (Depends on magnification and camera)	Sample Weight	≤ 2kg
Step Height Repeatability	≤ 0.3% 1 sigma	X/Y Axis Stroke	50 × 50mm (Manual)
Scan Velocity	8 ~ 40um/sec (User 5 selectable)	Z Axis Stroke	20mm(Manual)
Scan Method	Piezo @ Closed loop	Tilt Axis Stroke	± 2° (Manual)
Scan Range	≤ 100um (Piezo Option ≤ 250 um)	Work Table Size	120 × 120 mm
Objective Lens	Single Lens	Vibration Isolation	Passive Type (Vertical Resonance : 2.5 Hz)
Zoom Lens	1.0x	Weight	About 10kg
Camera	1/2" Mono Camera (Option : 2/3", 1")	Input Power	2φ, 110V/220V (± 10%) 15A, 50/60Hz
Illumination	White Light LED	Software	Surface View / Surface Map @ Window10 64bit
Filter	2 Filter Available (Manual)	*VSI : Visible Sandoz Interferometry *VEI : Visible Envelop Interferometry *VPI : Visible Phase-shift Interferometry	

Specification

Vertical Resolution	VSI, VEI < 0.5nm, VPI < 0.1nm	Sample Reflectivity	0.05 ~ 100%
Pixel Resolution	0.03 ~ 7.2um (Depends on magnification and camera)	Sample Weight	≤ 5kg
Step Height Repeatability	≤ 0.1% 1 sigma	X/Y Axis Stroke	50 × 50mm (Manual)
Scan Velocity	8 ~ 40um/sec (User 5 selectable)	Z Axis Stroke	30mm (Manual Coarse&Fine)
Scan Method	Piezo @ Closed loop	Tilt Axis Stroke	± 3° (Manual)
Scan Range	≤ 150um (Piezo Option≤300um)	Work Table Size	120 × 120mm
Objective Lens Turret	5 Lens Available (Manual Turret)	Vibration Isolation	Passive Type (Vertical Resonance : 2.5Hz)
Zoom Lens	1.0x	Weight	About 10kg
Camera	1/2" Mono Camera (Option : 2/3", 1")	Input Power	2φ, 110V/220V (± 10%) 15A, 50/60Hz
Illumination	White Light LED	Software	Surface View / Surface Map @ Window10 64bit
Filter	2 Filter Available (Automatic)	*VSI : Visible Sandoz Interferometry *VEI : Visible Envelop Interferometry *VPI : Visible Phase-shift Interferometry	

SURFIEW ELITE SERIES



Specification

Vertical Resolution	VSI, VEI < 0.5nm, VPI < 0.1nm
Pixel Resolution	0.03 ~ 7.2um (Depends on magnification and camera)
Step Height Repeatability	≤ 0.1% 1 sigma
Scan Velocity	8 ~ 40um/sec (User 5 selectable)
Scan Method	Piezo @ Closed loop
Scan Range	≤ 150um (Piezo Option≤300um / Motor Option ≤10mm)
Objective Lens Turret	5 Lens Available (Automatic Turret)
Zoom Lens Turret	2 Lens Available (Automatic)
Camera	1/2" Mono Camera (Option : 2/3", 1")
Illumination	White Light LED
Filter	2 Filter Available (Automatic)
Auto Focus	Image Auto Focus
Stitching	Yes
Sample Reflectivity	0.05 ~ 100%
Sample Weight	≤ 10kg
X/Y Axis Stroke	100 × 100mm (Automatic)
Z Axis Stroke	100mm (Automatic)
Tilt Axis Stroke	± 6° (Automatic)
Joystick	USB Joystick
Work Table Size	230 × 230mm
Vibration Isolation	Passive Type (Vertical Resonance : 1.5Hz)
Weight	About 45kg
Input Power	2φ , 110V/220V (±10%) 15A, 50/60Hz
Software	Surface View / Surface Map @ Window10 64bit

*VSI : Visible Sandoz Interferometry *VEI : Visible Envelop Interferometry *VPI : Visible Phase-shift Interferometry

SURFIEW PRO SERIES

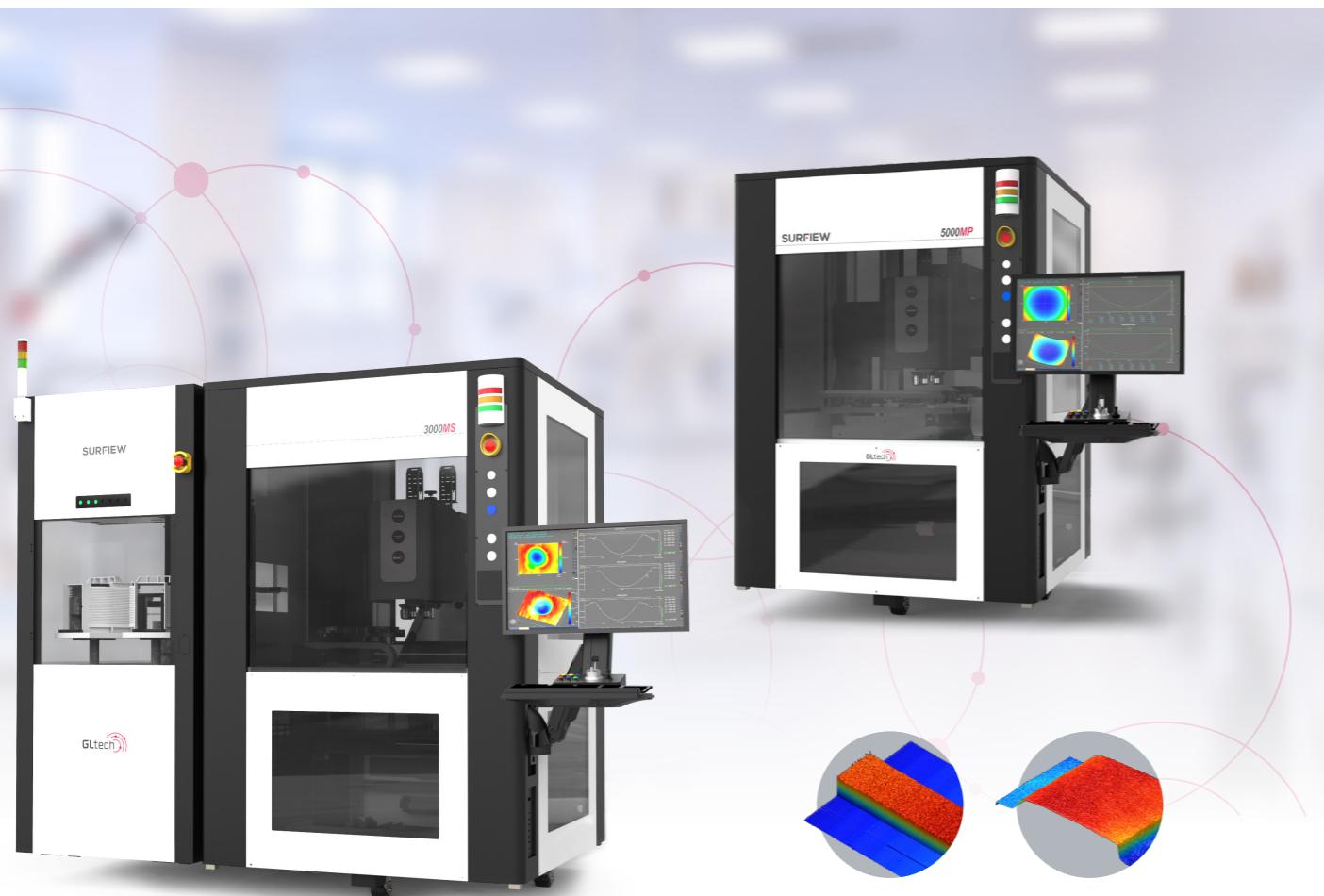


Specification

Vertical Resolution	VSI, VEI < 0.5nm, VPI < 0.1nm
Pixel Resolution	0.03 ~ 7.2um (Depends on magnification and camera)
Step Height Repeatability	≤ 0.1% 1 sigma
Scan Velocity	8 ~ 40um/sec (User 5 selectable)
Scan Method	Piezo @ Closed loop
Scan Range	≤ 150um (Piezo Option≤300um / Motor Option ≤10mm)
Objective Lens Turret	5 Lens Available (Automatic Turret)
Zoom Lens Turret	3 Lens Available (Automatic)
Camera	1/2" Mono Camera (Option : 2/3", 1")
Illumination	White Light LED
Filter	3 Filter Available (Automatic)
Auto Focus	Image Auto Focus
Stitching	Yes
Sample Reflectivity	0.05 ~ 100%
Sample Weight	≤ 20kg
X/Y Axis Stroke	300 × 300mm (Automatic)
Z Axis Stroke	100mm (Automatic)
Tilt Axis Stroke	± 6° (Automatic)
Joystick	Handwheel Joystick
Work Table Size	350 × 350mm
Vibration Isolation	Passive Type (Vertical Resonance : 1.5Hz)
Weight	About 400kg
Input Power	2φ , 110V/220V (±10%) 15A, 50/60Hz
Software	Surface View / Surface Map @ Window10 64bit

*VSI : Visible Sandoz Interferometry *VEI : Visible Envelop Interferometry *VPI : Visible Phase-shift Interferometry

SURFIEW MASTER SERIES



Specification

Vertical Resolution	VSI, VEI < 0.5nm, VPI < 0.1nm
Pixel Resolution	0.03 ~ 7.2um (Depends on magnification and camera)
Step Height Repeatability	≤ 0.1% 1 sigma
Scan Velocity	8 ~ 40um/sec (User 5 selectable)
Scan Method	Piezo @ Closed loop
Scan Range	≤ 300um (Motor Option ≤ 10mm)
Objective Lens Turret	6 Lens Available (Automatic Turret)
Zoom Lens Turret	5 Lens Available (Automatic)
Camera	1/2" Mono Camera (Option : 2/3", 1")
Illumination	White Light LED
Filter	3 Filter Available (Automatic)
Auto Focus	Image Auto Focus (Option :Laser AF)
*VSI : Visible Sandoz Interferometry *VEI : Visible Envelop Interferometry *VPI :Visible Phase-shift Interferometry	

SURFIEW PROBE MODULE



Specification

Scan Method	Piezo @ Closed loop
Scan Range	≤ 150um
Objective Lens Turret	5 Lens Available (Automatic Turret)
Zoom Lens	1.0x
Camera	1/2" Mono Camera
Illumination	White Light LED
Filter	2 Filter available (Automatic)

*VSI : Visible Sandoz Interferometry *VEI : Visible Envelop Interferometry *VPI :Visible Phase-shift Interferometry

Option

Interference Lens	2.5x, 5.0x, 10x, 20x, 50x, 100x
Objective Lens	2.5x, 5.0x, 10x, 20x, 50x, 100x
Zoom Lens	0.55x, 0.75x, 1.0x, 1.5x, 2.0x
Work Table	Porous Vacuum Type Rotation Table
Standard Sample	Height Standard Lateral Standard Roughness Standard

